

2020 IEEE Latin America Electron Devices Conference (LAEDC 2020)

**San Jose, Costa Rica
25 – 28 February 2020**



**IEEE Catalog Number: CFP20T67-POD
ISBN: 978-1-7281-1045-5**

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|-------------------------|-------------------|
| IEEE Catalog Number: | CFP20T67-POD |
| ISBN (Print-On-Demand): | 978-1-7281-1045-5 |
| ISBN (Online): | 978-1-7281-1044-8 |

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